



Docket No.: 50212-352

PATENT

. IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Michiko TAKUSHIMA, et al.

Serial No.: 10/082,134

Group Art Unit:

Filed: February 26, 2002

Examiner:

For:

LONG PERIOD GRATING AND MAKING METHOD OF THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

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Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

Registration No. 26,106

600 13th Street, N.W. Washington, DC 20005-3096 (202)756-8000 AJS:mlw

Facsimile: (202)756-8087 **Date: June 20, 2002**

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SHEET <u>1</u> OF <u>1</u>

INFORMATION DISCLOSURE CITATION IN AN APPLICATION				ATTY. DOCKET NO. 50212-352 (ADEMAR) 90/082,134				
•				APPLICANT Michiko TAKUSHIMA, et al.				
(PTO-1449)				FILING DATE February 2	GROUP			
		U	S. PATENT	DOCUMENT	ΓS	*		
EXAMINER'S INITIALS	PATENT NO.	DATE	1	IAME	CLASS	SUBCLASS	FILING DATE	
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FOREIGN PATENT DOCUMENTS								
EXAMINER'S INITIALS	PATENT NO.	DATE	СО	UNTRY	CLASS	SUBCLASS	Yes	Translation No
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	OTHER	ART (Inclu	ding Author	, Title, Date, I	Pertinent P	ages, Etc.)		- 4 · ·
	"Compact long Electronics Let					s", M. HAR	UMOT	TO et al.,
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EXAMINER			D	ATE CONSID	ERED			